


<b>Search Notes</b>  	<b>Application/Control No.</b>  10758828	<b>Applicant(s)/Patent Under Reexamination</b>  LEMAY ET AL.
	<b>Examiner</b>  Lee, Benjamin W	<b>Art Unit</b>  3709

SEARCHED			
Class	Subclass	Date	Examiner
463	24, 29, 34	12-7-2006	BWL
345	547-549	12-7-2006	BWL

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Name Search	12-7-2006	BWL
Assignee Search	12-7-2006	BWL
Consulted with Kim Nguyen, Cls. 463, 345	12-5-2006	BWL
PLUS Search	12-4-2006	BWL
East Text Search (see attached "Search History")	12-8-2006	BWL
Backward/Forward Search	12-8-2006	BWL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner